

<b>Notice of References Cited</b>	Application/Control No. 10/580,401		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner AWET HAILE		Art Unit 2474	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0059432 A1	05-2002	Masuda et al.	709/227
*	B	US-2003/0076829 A1	04-2003	Rabie et al.	370/391
*	C	US-2004/0202159 A1	10-2004	Matsubara et al.	370/389
*	D	US-7,047,316 B2	05-2006	Iwata et al.	709/240
*	E	US-2006/0182119 A1	08-2006	Li et al.	370/395.52
*	F	US-7,215,640 B2	05-2007	Matsubara, Daisuke	370/235
*	G	US-7,477,657 B1	01-2009	Murphy et al.	370/468
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.